

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>	
	10724552	KOSTRZEWSKI ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Chawan, Sheela C	2624	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	115, 211, 278	2/16/07	SCC
356	300	"	"
359	11	"	"
ABOVE SEARCH UP- DATE.		"	"

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST,US-PGPUB,USPAT,EPO,JPO,DERWENT, IBM-TDB, SEE SEARCH HISTORY.	2/16/07	SCC
382/115, 116,124, 278.CCLS, US-PATENT ONLY, SEE TEXT SEARCH.	"	"
359/3,11,15,29,34,561,559.CCLS.	"	"
356/300,347.CCLS.	"	"
INVENTOR NAME SEARCH.	"	"
INTERFERENCE SEARCH SEE SEARCH HISTORY.	"	"
CLASS 359/125, ABOLISH.	"	"
CLASS 356/347, ABOLISH.	"	"
SEARCH IEEE OR INSPEC DATA BASE.	"	"

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	115, 211, 278	2/16/07	SCC
359	11	"	"
356	300	"	"